

<b>Notice of References Cited</b>		Application/Control No. 10/711,418	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
		Examiner Stacy A. Whitmore	Art Unit 2825	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Schmidt, J., et al., "A possible technique for determining the average grain size in thin granular superconducting films", March 1987, IEEE, IEEE Transactions on Magnetics, Vol. 23, Issue 2, pages 1034-1036.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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